

APPLICATION NOTE

QPlus AFM on NaCl (001) at low oscillation amplitudes using Matrix 4 AFM PLL with TipGuard

Date: 14.03.2018

By: Jürgen Köble

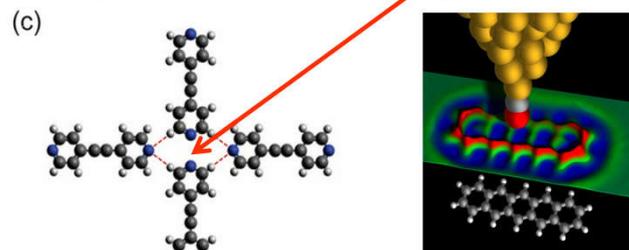
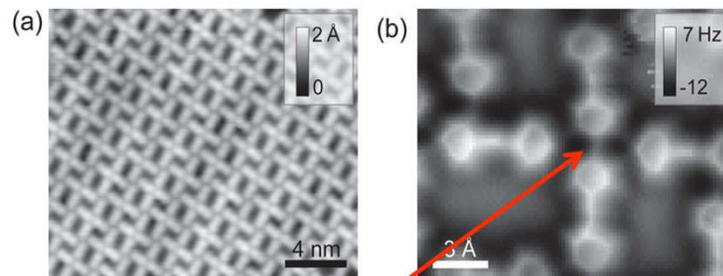
Instrument Configuration

LT STM

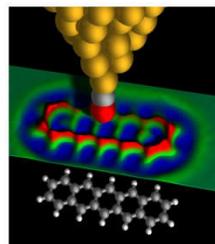
Matrix 4 with new AFM PLL

Improved QPlus AFM sensors

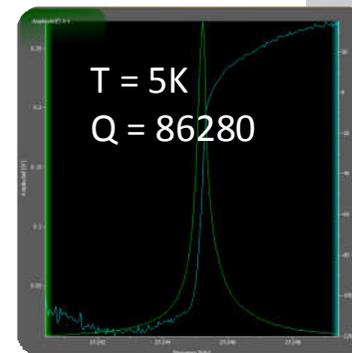
- **Newest Generation of Giessibl sensors**
- **Integrated electrodes**
- **New high precision manufacturing**
- **Higher Q-factor ≈ 90.000 at $T=5K$**
- **Better reliability**



Sampsa K. Hämmäläinen et al.: Phys. Rev. Lett. 113, 186102



Schematic of CO functionalized tip

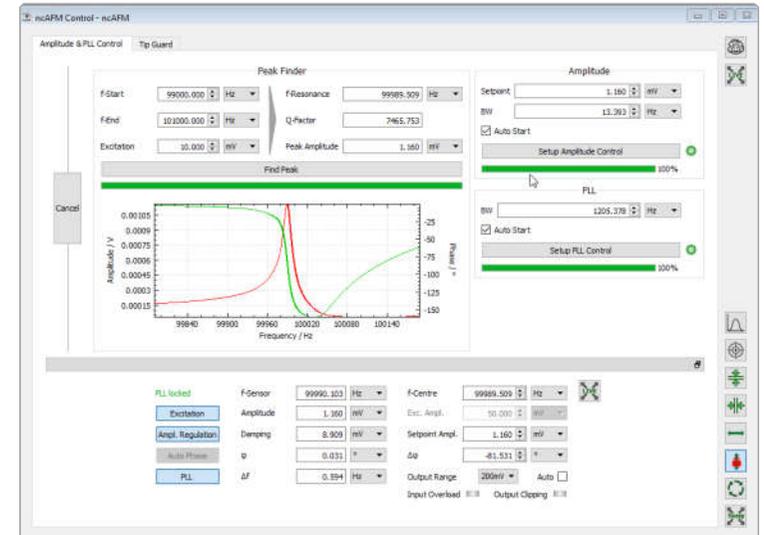


The new Matrix 4 – High Performance QPlus

- More compact
- Better usability and accessibility
- Full 64bit Software
- Software coarse motor control

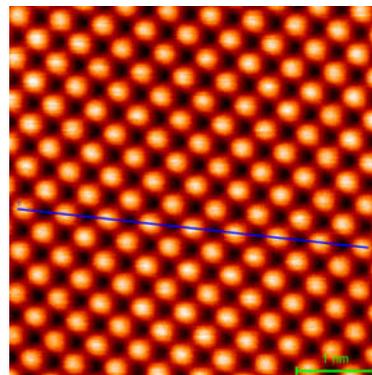


- Full Matrix integration for ease of use



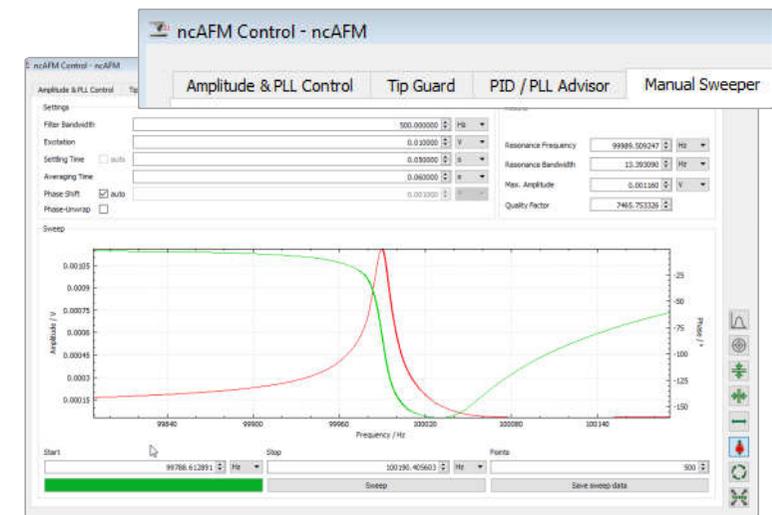
- Highest performance QPlus AFM hardware powered by

Zurich Instruments

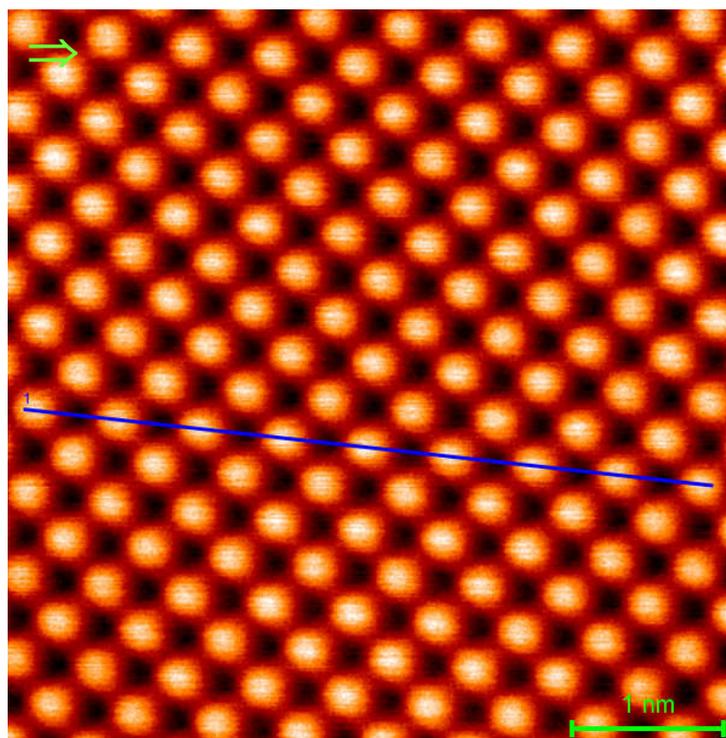


NaCl (001)

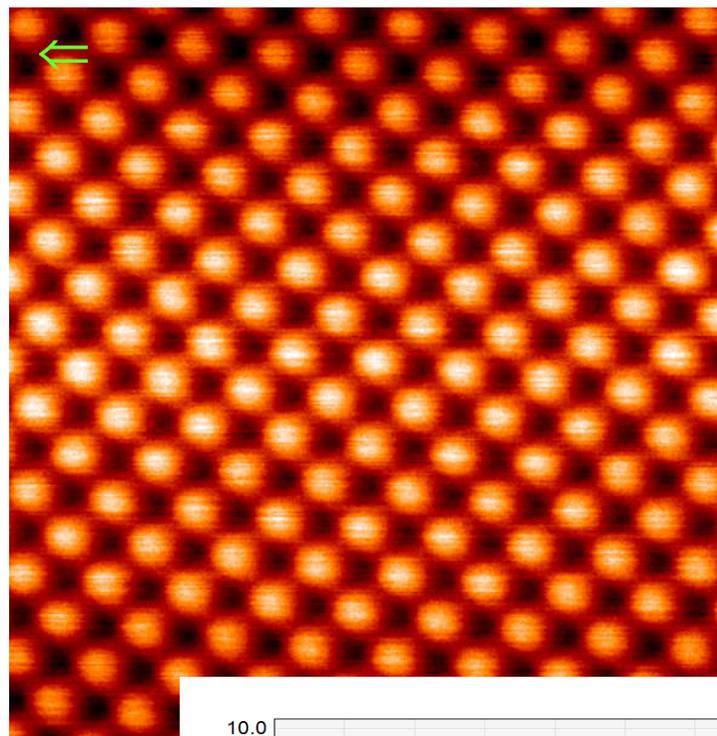
- TipGuard phase & amplitude tip protection
- Oscillation Autofinder robust swarm technology algorithm



NaCl(001) with new AFM Control Unit and LT STM



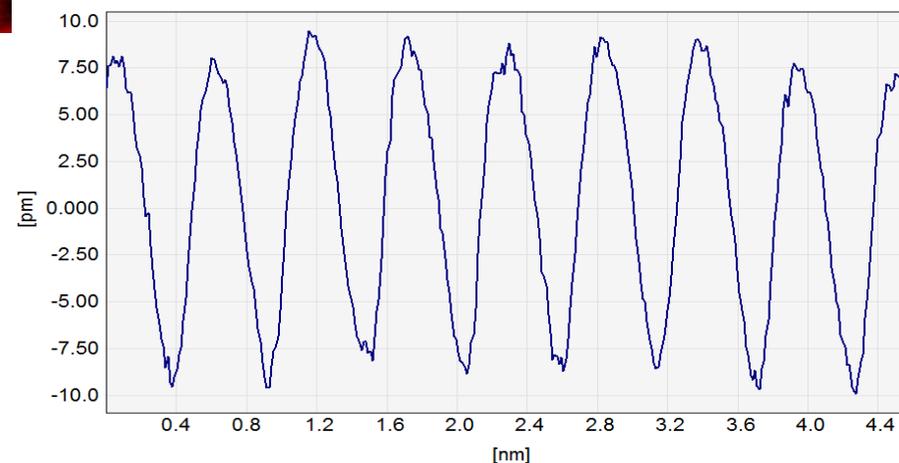
linewise
slope
subtract



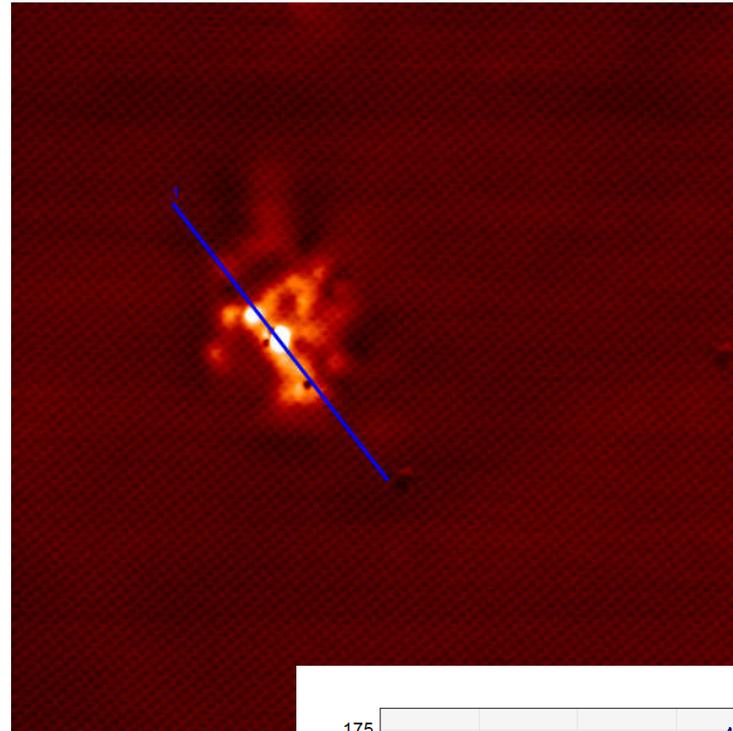
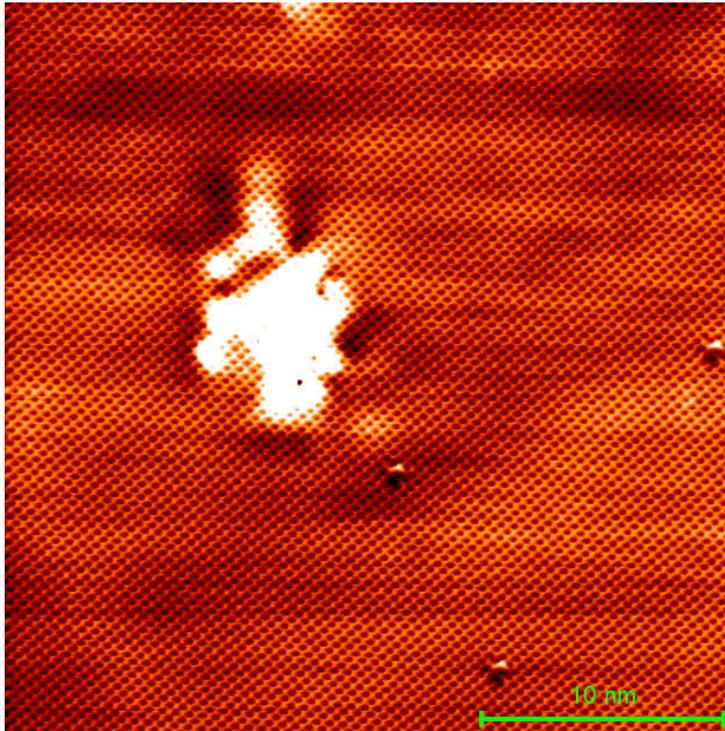
plane
subtract

$A = 500\text{pm}$
 $\Delta f_{\text{set}} = -5.81\text{Hz}$
 $Q = 30\text{k}$
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 10\text{Hz}$
 $BW_{\text{PLL}} = 82\text{Hz}$

- **Constant Δf topography imaged with QPlusTM sensor (Giessbl single prongue).**

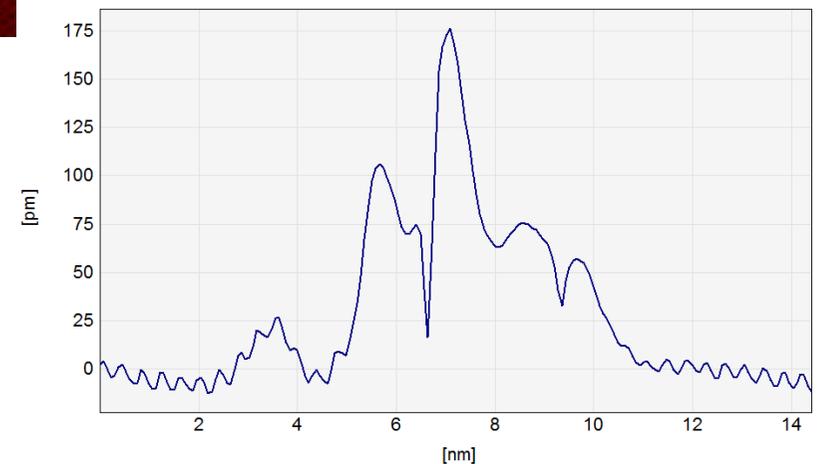


NaCl(001): Defect/Adsorbate imaging

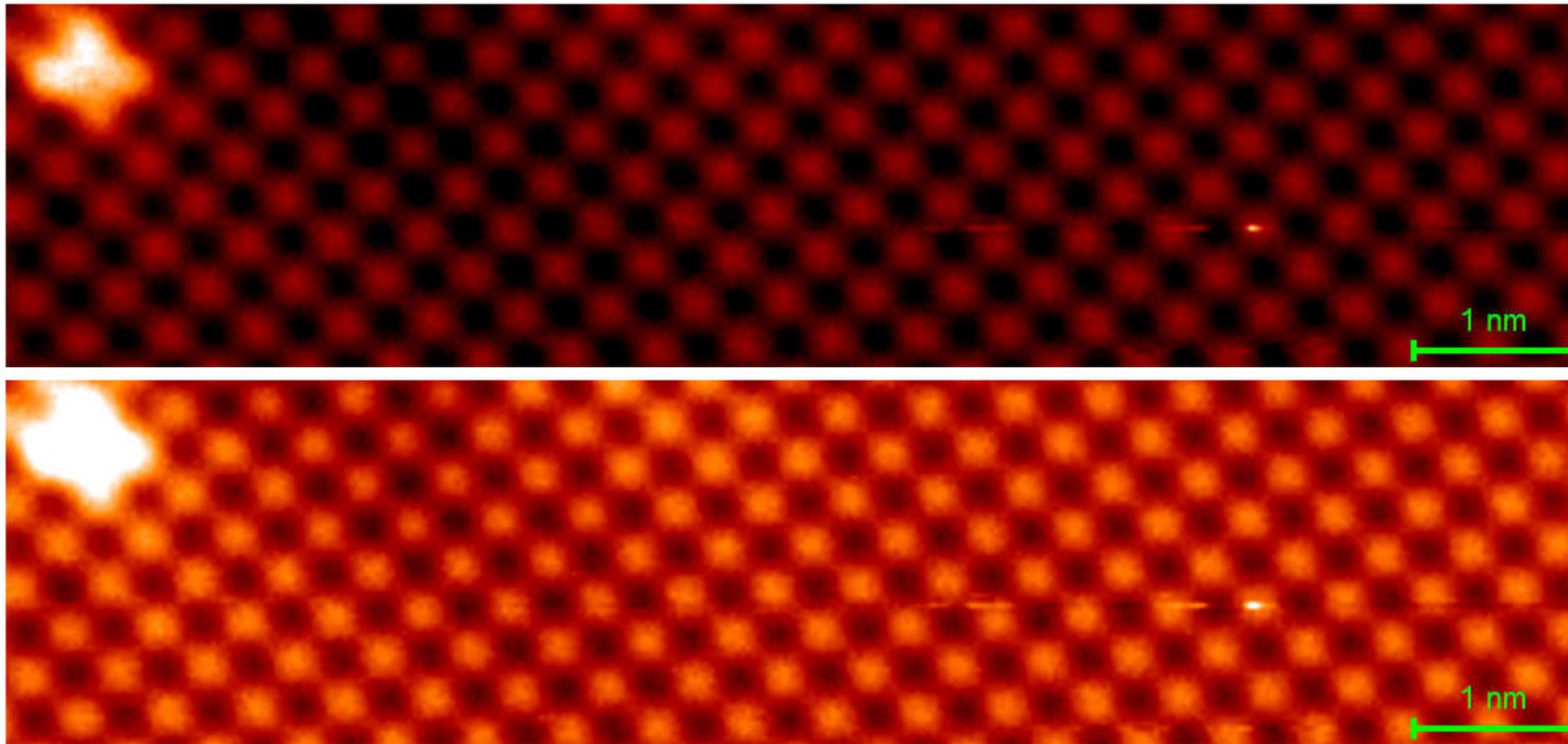


$A = 500\text{pm}$
 $\Delta f_{\text{set}} = -9.5\text{Hz}$
 $Q = 30\text{k}$
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 10\text{Hz}$
 $BW_{\text{PLL}} = 82\text{Hz}$

- **Constant Δf topography imaged with defect or adsorbate**
- **Stable imaging even on charged defect region**



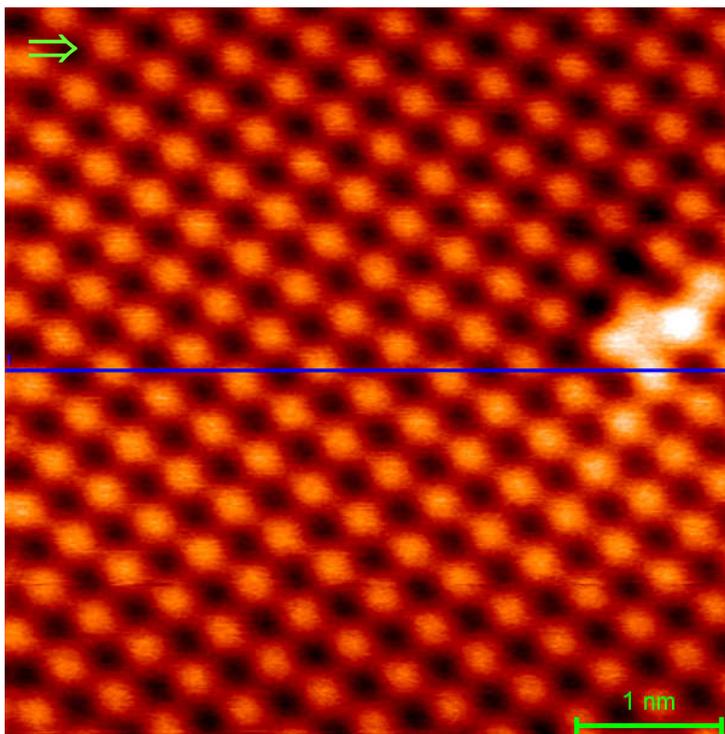
NaCl(001): Defect/Adsorbate imaging



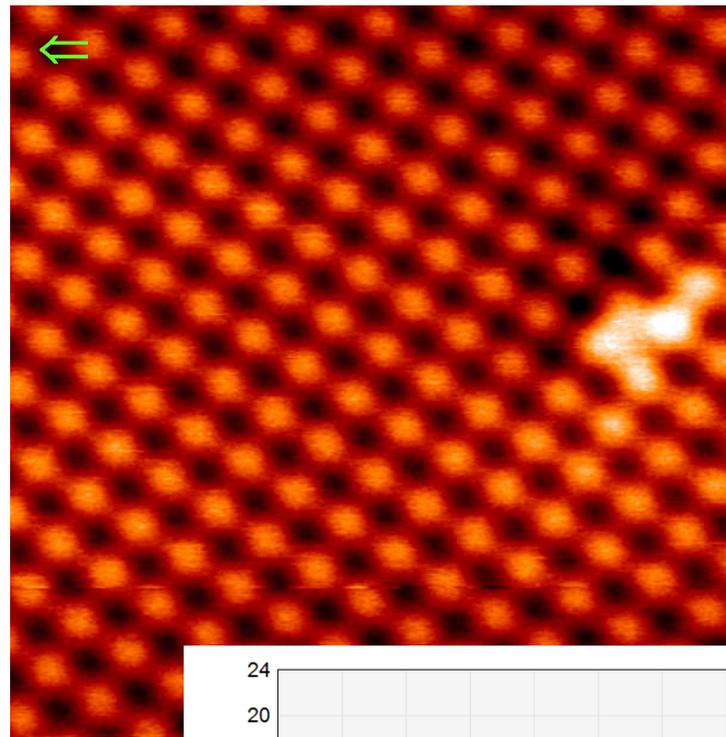
$A = 500\text{pm}$
 $\Delta f_{\text{set}} = -8.5\text{Hz}$
 $Q = 30\text{k}$
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 10\text{Hz}$
 $BW_{\text{PLL}} = 82\text{Hz}$

- **Constant Δf topography imaged with defect or adsorbate**
- **Local charges usually destabilize the feedback loop. Here the image runs without any distortions.**

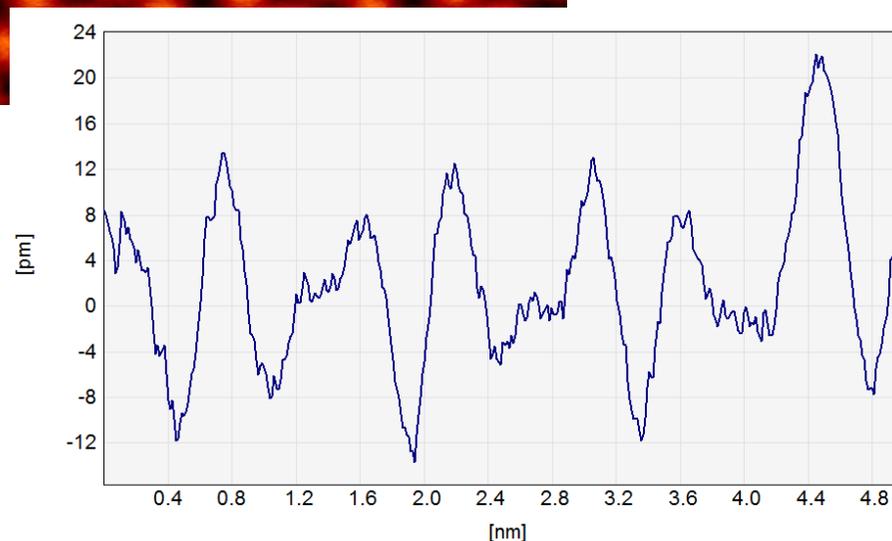
Constant Δf imaging at various amplitudes – 500pm



Raw Data (plane subtract only)

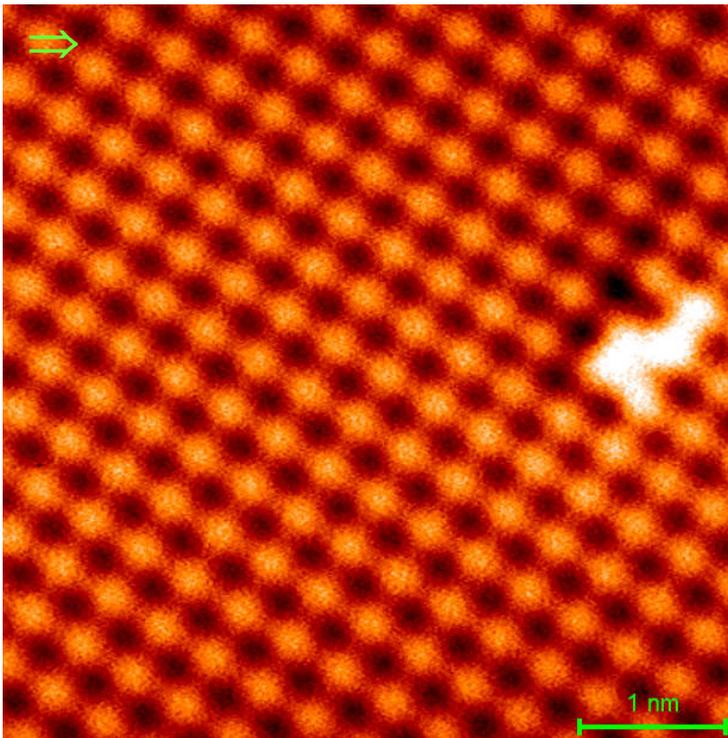


$A = 500\text{pm}$
 $\Delta f_{\text{set}} = -3.07\text{Hz}$
 $Q = 55\text{k}$
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 4\text{Hz}$
 $BW_{\text{PLL}} = 36\text{Hz}$

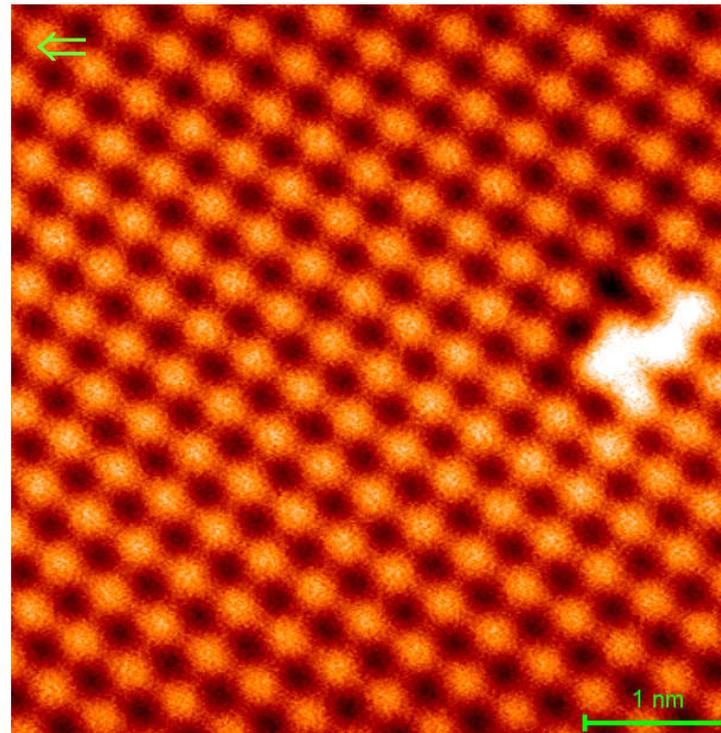


- **Constant Δf topography imaged with defect or adsorbate imaged at large amplitude with best S/N at 500pm oscillation amplitude.**

Constant Δf imaging at various amplitudes – 100pm



Raw Data (plane subtract only)

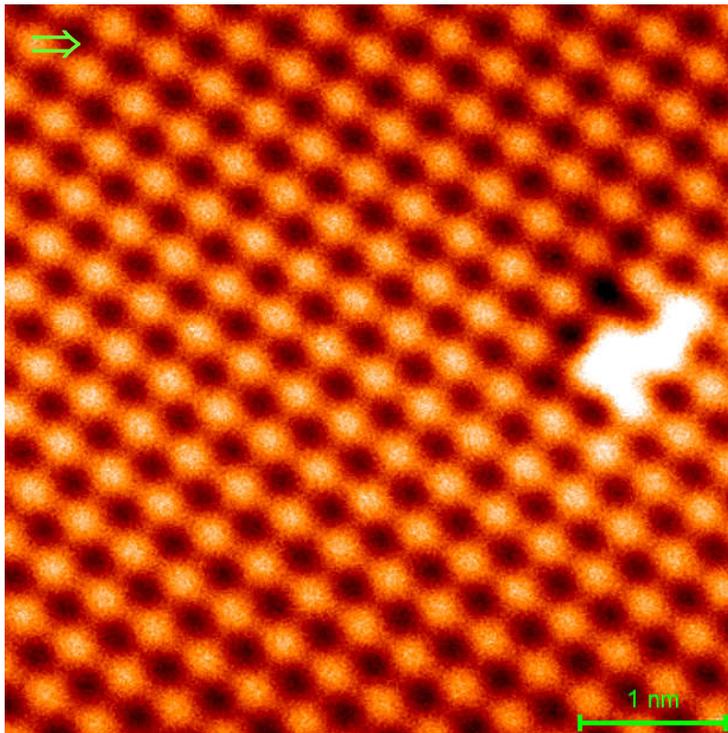


A = 100pm
 $\Delta f_{\text{set}} = -5.0\text{Hz}$
Q = 55k
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 4\text{Hz}$
 $BW_{\text{PLL}} = 36\text{Hz}$
Tip Guard on

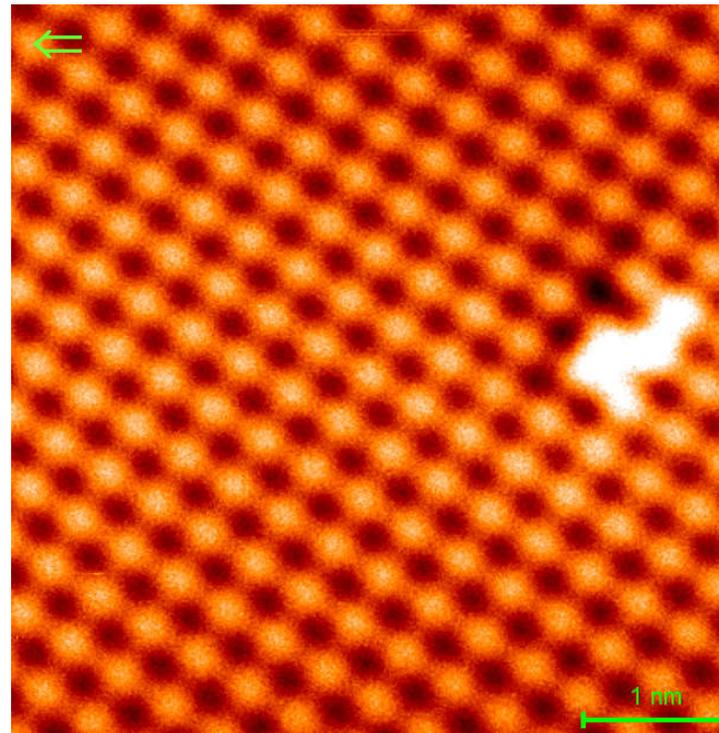
- **Constant Δf topography imaged with defect or adsorbate**
- **Imaged at 100pm oscillation amplitude.**

- **Matrix TipGuard activated**

Constant Δf imaging at various amplitudes – 50pm



Raw Data (plane subtract only)

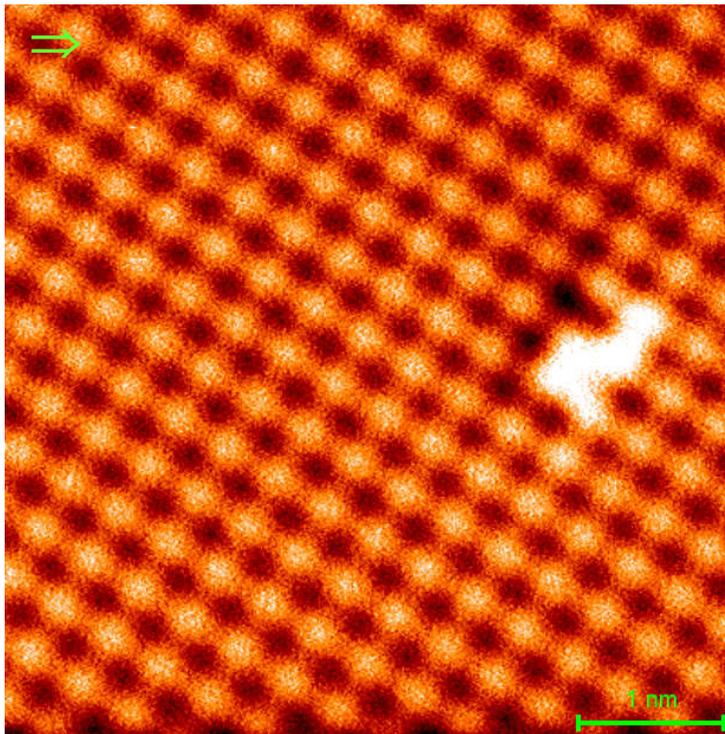


A = 50pm
 $\Delta f_{\text{set}} = -5.25\text{Hz}$
Q = 55k
 $f_{\text{res}} = 27\text{kHz}$
 $\text{BW}_A = 4\text{Hz}$
 $\text{BW}_{\text{PLL}} = 36\text{Hz}$
Tip Guard on

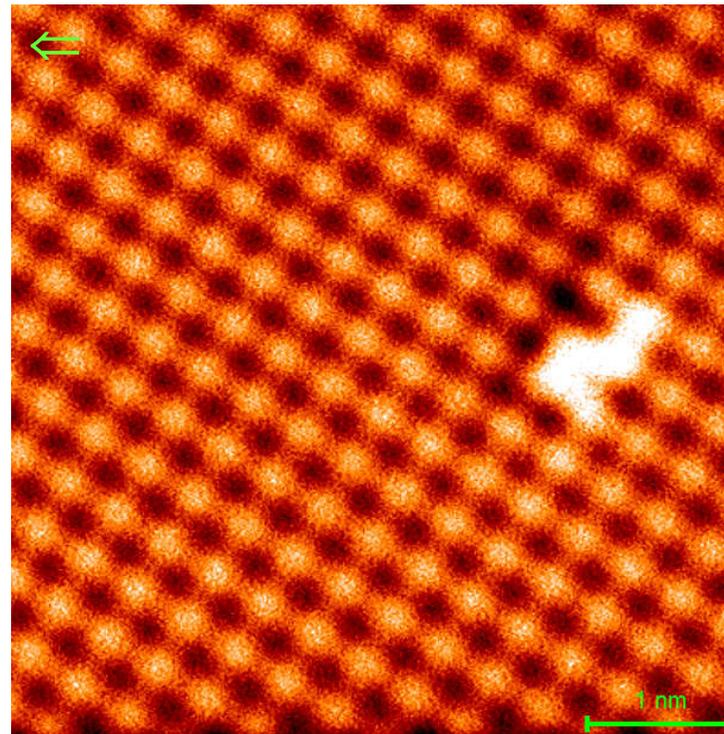
- **Constant Δf topography imaged with defect or adsorbate**
- **Imaged at 50pm oscillation amplitude**

- **Matrix TipGuard activated**

Constant Δf imaging at various amplitudes – 25pm



Raw Data (plane subtract only)

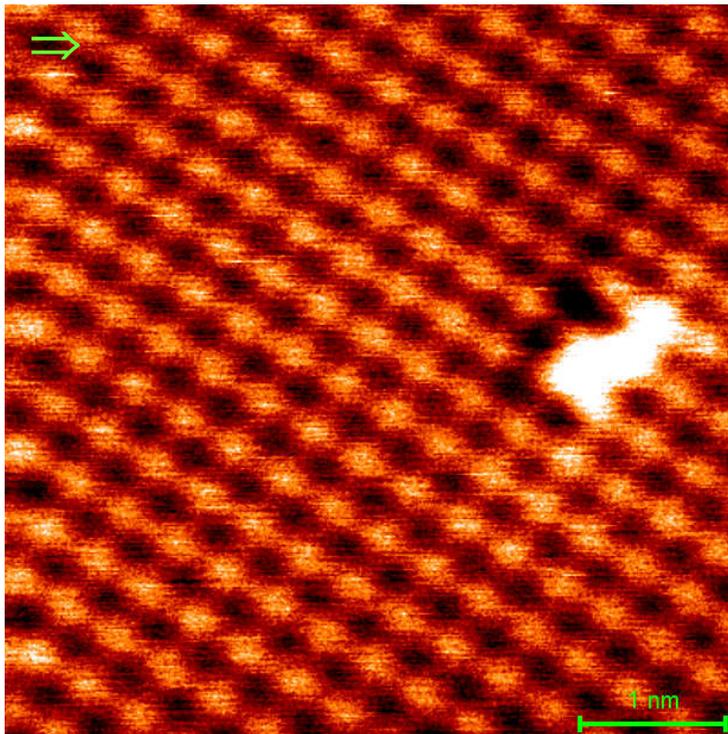


A = 25pm
 $\Delta f_{\text{set}} = -5.25\text{Hz}$
Q = 55k
 $f_{\text{res}} = 27\text{kHz}$
 $\text{BW}_A = 2\text{Hz}$
 $\text{BW}_{\text{PLL}} = 25\text{Hz}$
Tip Guard on

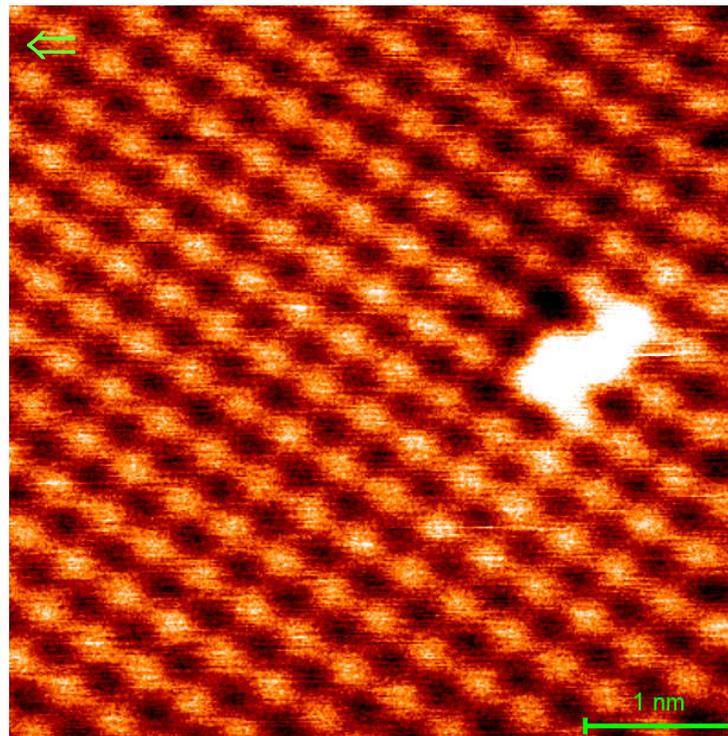
- **Constant Δf topography imaged with defect or adsorbate**
- **Imaged at 25pm oscillation amplitude**

- **Matrix TipGuard activated**

Constant Δf imaging at various amplitudes – 10pm



Raw Data (plane subtract only)

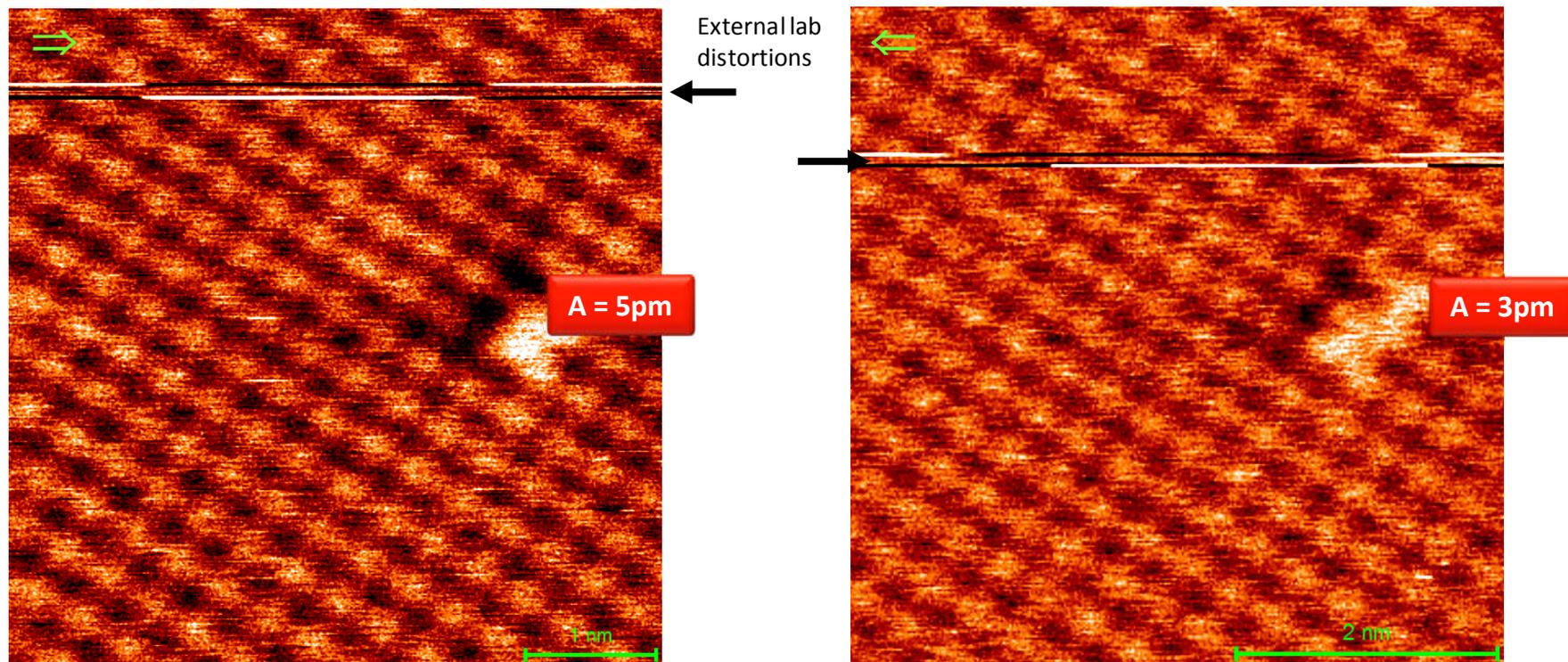


A = 10pm
 $\Delta f_{\text{set}} = -5.25\text{Hz}$
Q = 55k
 $f_{\text{res}} = 27\text{kHz}$
 $\text{BW}_A = 2\text{Hz}$
 $\text{BW}_{\text{PLL}} = 25\text{Hz}$
Tip Guard on

- **Constant Δf topography imaged with defect or adsorbate**
- **Imaged at 10pm oscillation amplitude**

- **Matrix TipGuard activated**

Constant Δf imaging at various amplitudes – 5pm and 3pm



Raw Data (linewise slope subtract)

A = 5pm

$\Delta f_{\text{set}} = -5.25\text{Hz}$

Q=55k

$f_{\text{res}} = 27\text{kHz}$

$\text{BW}_A = 2\text{Hz}$

$\text{BW}_{\text{PLL}} = 25\text{Hz}$

- Constant Δf topography imaged with defect or adsorbate
- Imaged at smallest oscillation amplitudes

A = 3pm

$\Delta f_{\text{set}} = -5.25\text{Hz}$

Q=55k

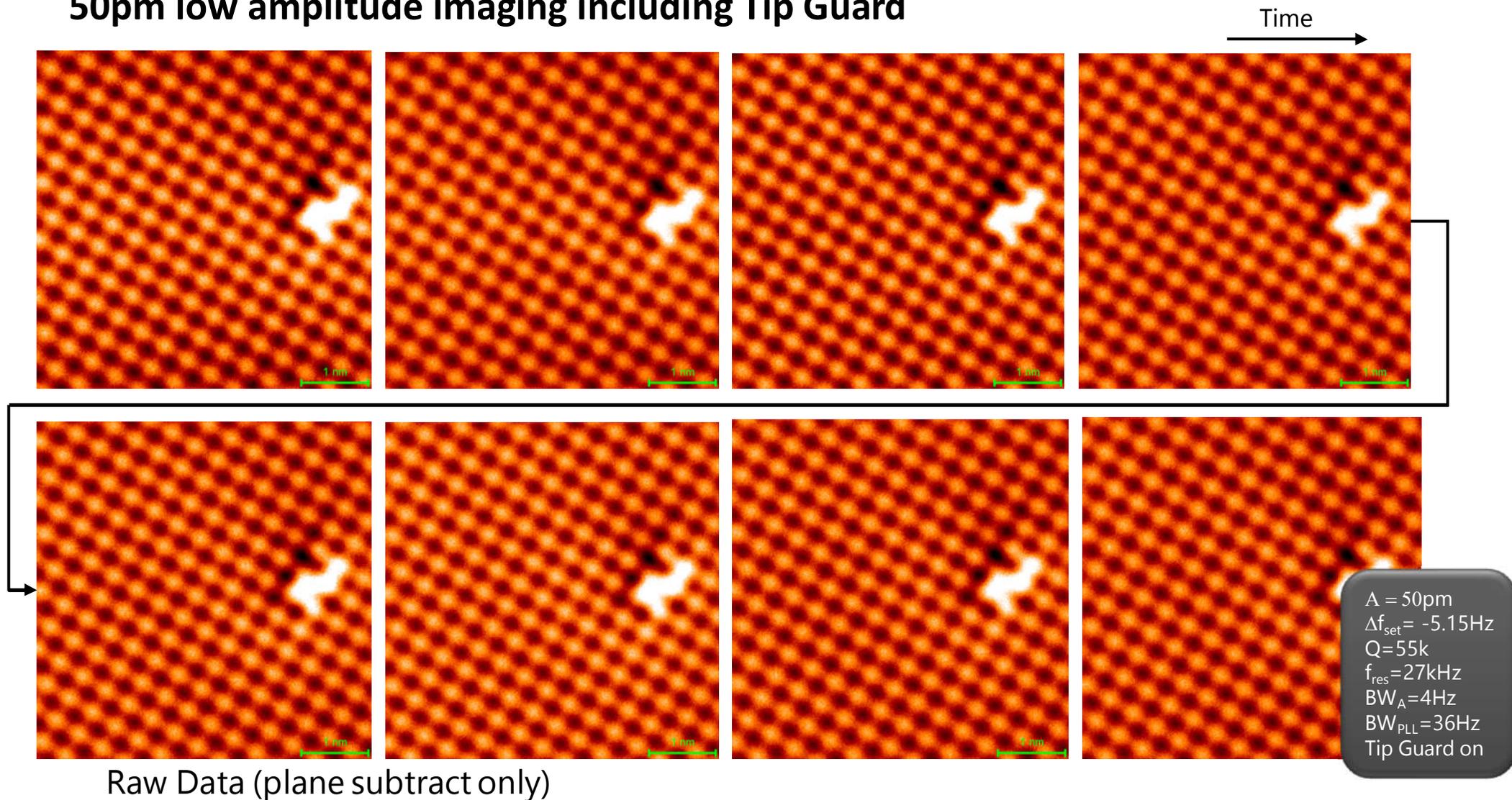
$f_{\text{res}} = 27\text{kHz}$

$\text{BW}_A = 2\text{Hz}$

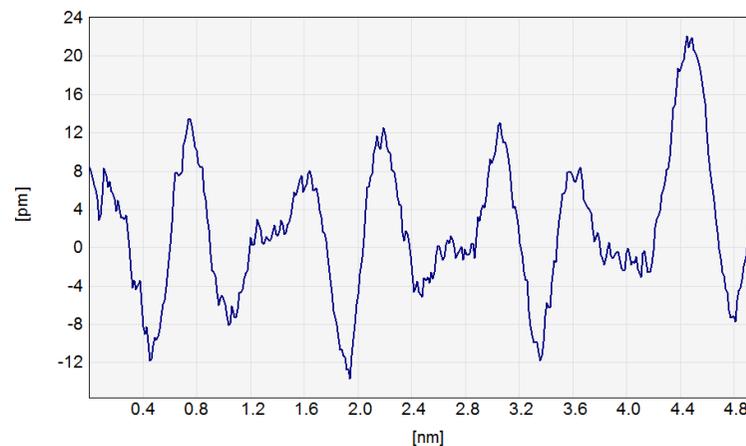
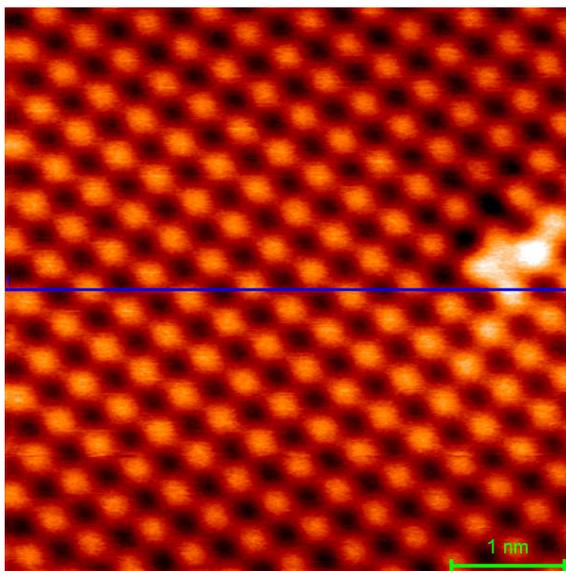
$\text{BW}_{\text{PLL}} = 25\text{Hz}$

High stability at 50pm - Image series 8h

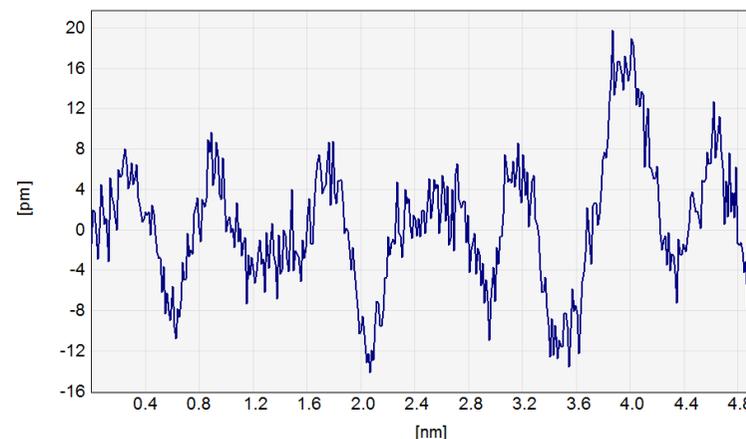
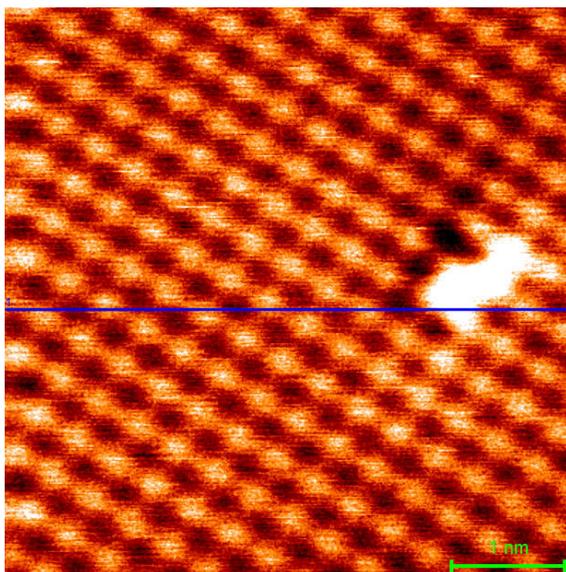
- **Constant Δf topography imaging sequence showing stability of 50pm low amplitude imaging including Tip Guard**



Comparison of line profiles



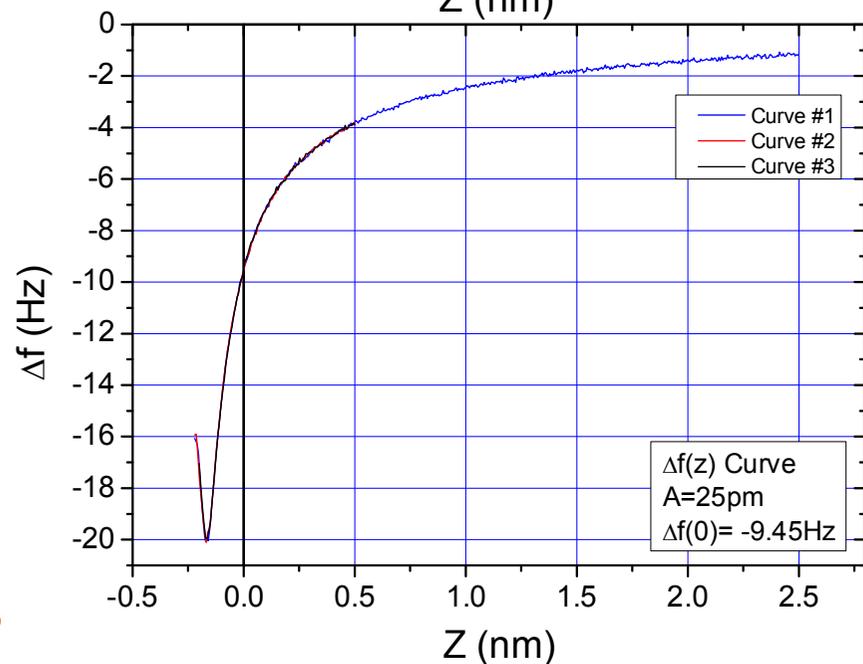
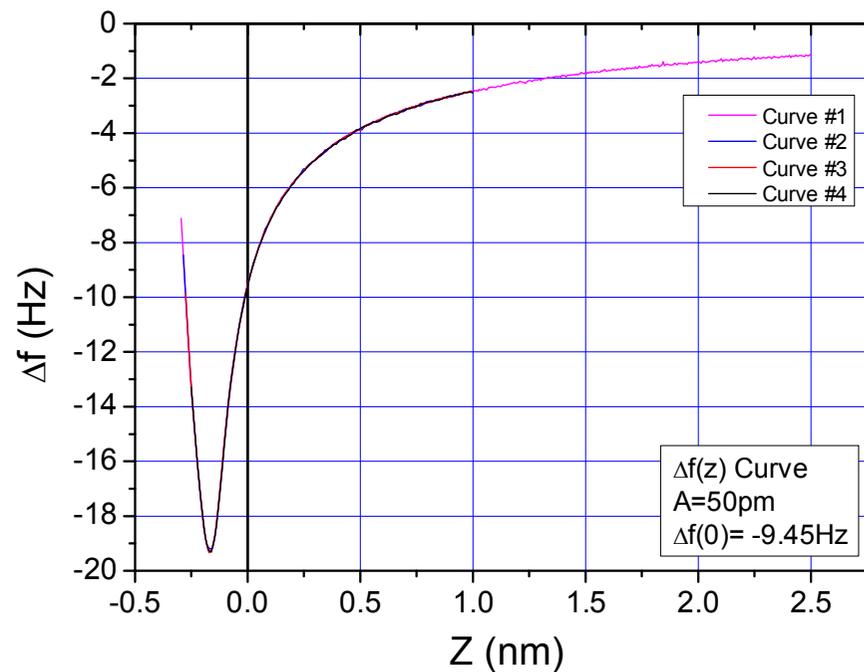
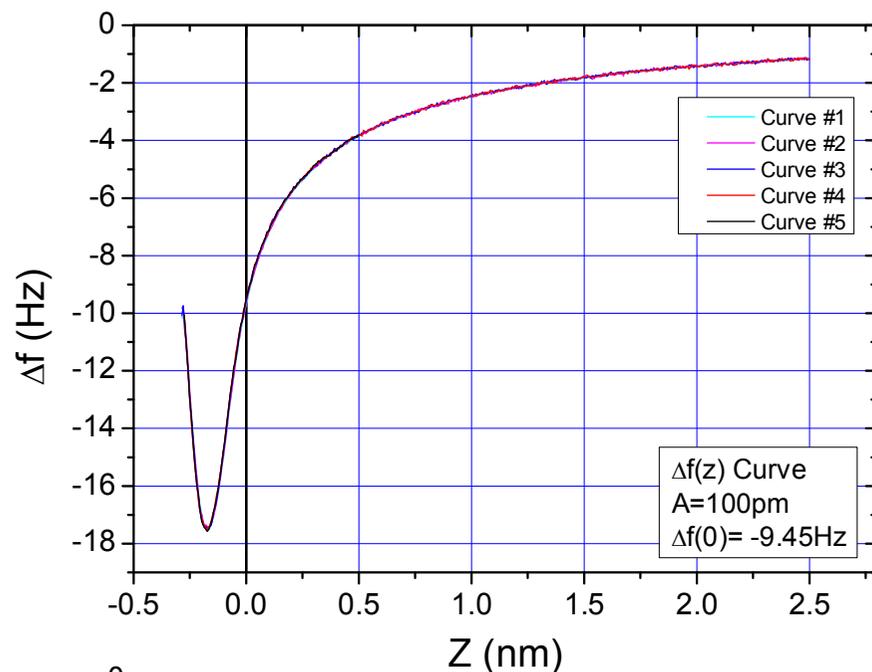
A = 500pm
 $\Delta f_{\text{set}} = -3.07\text{Hz}$
Q=55k
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 4\text{Hz}$
 $BW_{\text{PLL}} = 36\text{Hz}$



A = 10pm
 $\Delta f_{\text{set}} = -5.25\text{Hz}$
Q=55k
 $f_{\text{res}} = 27\text{kHz}$
 $BW_A = 2\text{Hz}$
 $BW_{\text{PLL}} = 25\text{Hz}$
Tip Guard on

Raw Data (plane subtract only)

Force spectroscopy at various amplitudes



- High reproducibility and low noise down to 25pm amplitude.

Summary

- **LT STM with record proven scientific output on leading-edge QPlus AFM research**
- **AFM PLL based on Zürich Instruments electronics proving best S/N performance on the market**
- **Fully integrated with Matrix providing ease-of-use and *TipGuard* for stable imaging**
- **New manufacturing process for QPlus sensors with extremely high Q factor**

- **Oscillation amplitudes down to 3pm on NaCl(001)**
- **Impressive long-term imaging stability using *TipGuard***
- **Stable imaging even on charged defect regions**